

January 2015

# FDMS86350ET80

# N-Channel PowerTrench<sup>®</sup> MOSFET 80 V, 198 A, 2.4 m $\Omega$

#### **Features**

- Extended T<sub>J</sub> rating to 175°C
- Max  $r_{DS(on)}$  = 2.4 m $\Omega$  at  $V_{GS}$  = 10 V,  $I_D$  = 25 A
- Max  $r_{DS(on)} = 3.2 \text{ m}\Omega$  at  $V_{GS} = 8 \text{ V}$ ,  $I_D = 22 \text{ A}$
- Advanced Package and Silicon combination for low r<sub>DS(on)</sub> and high efficiency
- MSL1 robust package design
- 100% UIL tested
- RoHS Compliant

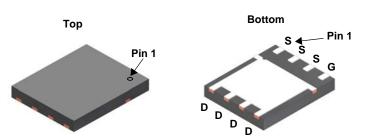


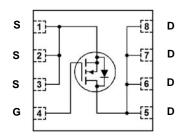
## **General Description**

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced Power Trench® process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

## **Applications**

- Primary MOSFET
- Synchronous Rectifier
- Load Switch
- Motor Control Switch





Power 56

# **MOSFET Maximum Ratings** $T_A = 25$ °C unless otherwise noted

Symbol	Parame	eter		Ratings	Units
$V_{DS}$	Drain to Source Voltage			80	V
$V_{GS}$	Gate to Source Voltage			±20	V
	Drain Current -Continuous	T <sub>C</sub> = 25 °C	(Note 5)	198	
	-Continuous	T <sub>C</sub> = 100 °C	(Note 5)	140	^
I <sub>D</sub>	-Continuous	T <sub>A</sub> = 25 °C	(Note 1a)	25	A
	-Pulsed		(Note 4)	693	
E <sub>AS</sub>	Single Pulse Avalanche Energy		(Note 3)	864	mJ
Б	Power Dissipation	T <sub>C</sub> = 25 °C		187	W
$P_{D}$	Power Dissipation	T <sub>A</sub> = 25 °C	(Note 1a)	3.3	VV
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Tempera	ature Range		-55 to +175	°C

### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.8	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	45	C/VV

#### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS86350ET	FDMS86350ET80	Power 56	13 "	12 mm	3000 units

## **Electrical Characteristics** $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
$BV_DSS$	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	80			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, referenced to 25 °C		45		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 64 V, V <sub>GS</sub> = 0 V			1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA

#### **On Characteristics**

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	2.5	3.8	4.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, referenced to 25 °C		-12		mV/°C
r <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 25 \text{ A}$		2.0	2.4	mΩ
		$V_{GS} = 8 \text{ V}, I_D = 22 \text{ A}$		2.5	3.2	
		$V_{GS} = 10 \text{ V}, I_D = 25 \text{ A}, T_J = 125 ^{\circ}\text{C}$		3.1	3.8	
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 5 \text{ V}, I_{D} = 25 \text{ A}$		70		S

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	10 1/ 1/ 0 1/		8030		pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1  MHz		1370		pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1 1011 12		31		pF
$R_g$	Gate Resistance		0.1	1.1	3	Ω

#### **Switching Characteristics**

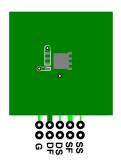
t <sub>d(on)</sub>	Turn-On Delay Time		50	80	ns
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = 40 V, I <sub>D</sub> = 25 A,	34	55	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$	40	65	ns
t <sub>f</sub>	Fall Time		11	20	ns
$Q_g$	Total Gate Charge	V <sub>GS</sub> = 0 V to 10 V	110	155	nC
Qg	Total Gate Charge	$V_{GS} = 0 \text{ V to 8 V}$ $V_{DD} = 40 \text{ V},$	90	127	nC
Q <sub>gs</sub>	Gate to Source Charge	I <sub>D</sub> = 25 A	46		nC
$Q_{gd}$	Gate to Drain "Miller" Charge		23		nC

### **Drain-Source Diode Characteristics**

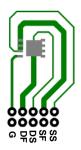
$V_{SD}$	Source to Drain Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 2.1 A (Note 2)	0.71	1.2	V
	Source to Drain Diode Polward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 25 A (Note 2)	0.79	1.3	
t <sub>rr</sub>	Reverse Recovery Time	I <sub>E</sub> = 25 A, di/dt = 100 A/μs	63	101	ns
Q <sub>rr</sub>	Reverse Recovery Charge	-1 <sub>F</sub> = 25 A, α//αt = 100 A/μs	62	100	nC

#### Notes:

1. R<sub>0JA</sub> is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>0CA</sub> is determined by the user's board design.



a. 45 °C/W when mounted on a 1 in² pad of 2 oz copper.



b. 115 °C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width < 300  $\mu\text{s},$  Duty cycle < 2.0%.
- 3.  $E_{AS}$  of 864 mJ is based on starting  $T_J$  = 25 °C, L = 3 mH,  $I_{AS}$  = 24 A,  $V_{DD}$  = 80 V,  $V_{GS}$  = 10 V, 100% test at L = 0.1 mH,  $I_{AS}$  = 74 A.
- 4. Pulse Id please refer to Fig.11 SOA curve for more details.
- 5. Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal & electro-mechanical application board design.

# Typical Characteristics $T_J = 25$ °C unless otherwise noted

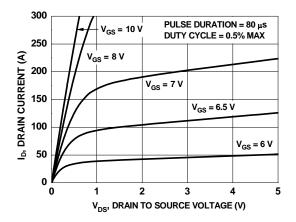


Figure 1. On-Region Characteristics

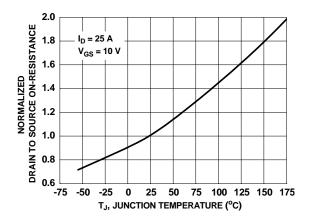


Figure 3. Normalized On-Resistance vs Junction Temperature

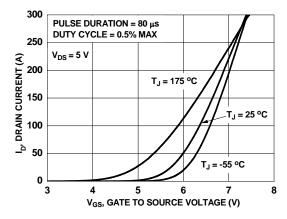


Figure 5. Transfer Characteristics

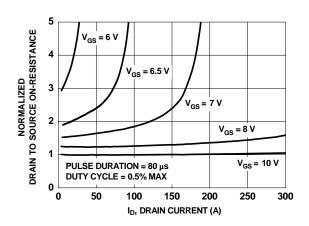


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

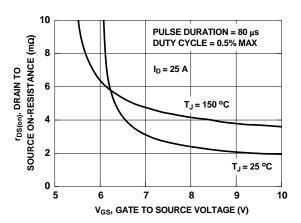


Figure 4. On-Resistance vs Gate to Source Voltage

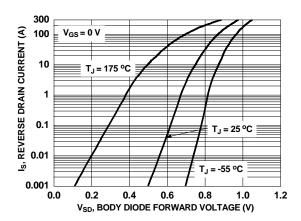


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

## **Typical Characteristics** $T_J = 25$ °C unless otherwise noted

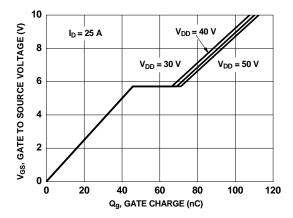


Figure 7. Gate Charge Characteristics

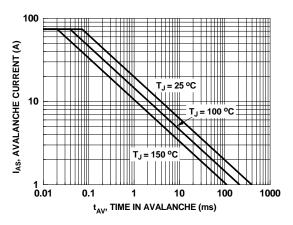


Figure 9. Unclamped Inductive Switching Capability

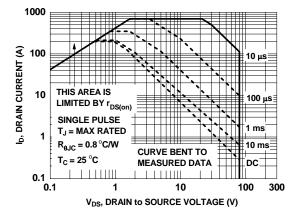


Figure 11. Forward Bias Safe Operating Area

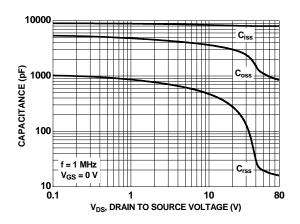


Figure 8. Capacitance vs Drain to Source Voltage

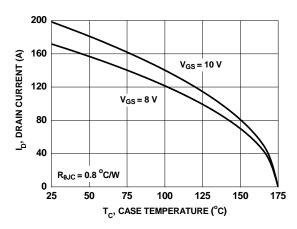


Figure 10. Maximum Continuous Drain Current vs Case Temperature

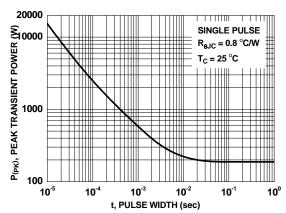


Figure 12. Single Pulse Maximum Power Dissipation

## **Typical Characteristics** T<sub>J</sub> = 25 °C unless otherwise noted

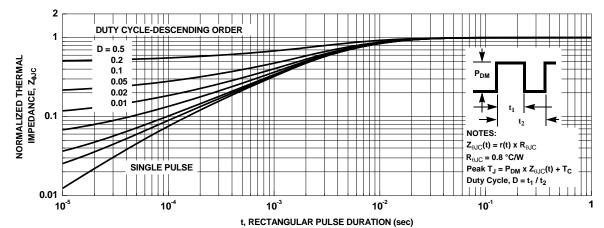
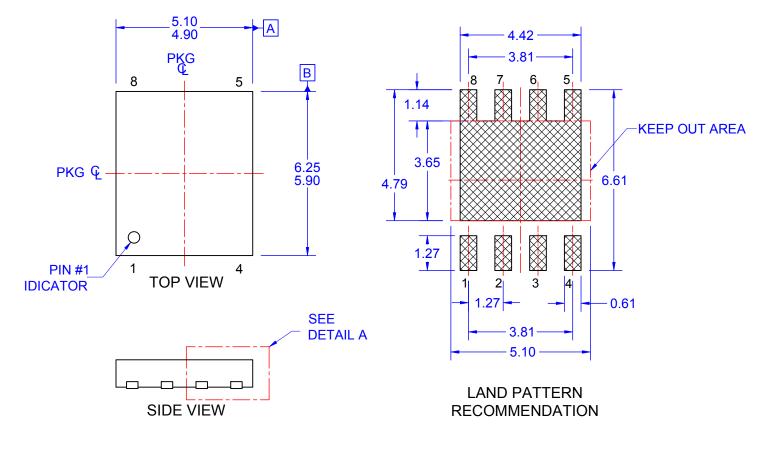
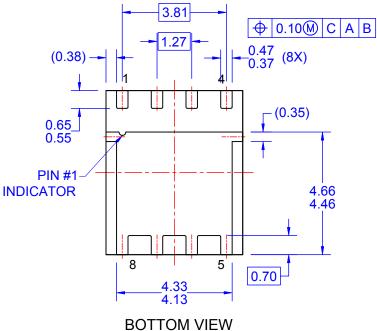
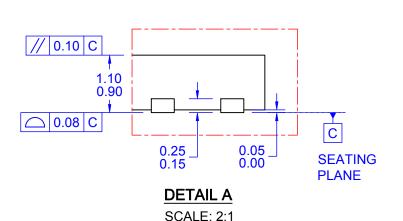


Figure 13. Junction-to-Case Transient Thermal Response Curve







NOTES: UNLESS OTHERWISE SPECIFIED

- A) PACKAGE STANDARD REFERENCE: JEDEC MO-240, ISSUE A, VAR. AA,
- B) ALL DIMENSIONS ARE IN MILLIMETERS.
- C) DIMENSIONS DO NOT INCLUDE BURRS OR MOLD FLASH. MOLD FLASH OR BURRS DOES NOT EXCEED 0.10MM.
- D) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-2009.
- E) IT IS RECOMMENDED TO HAVE NO TRACES OR VIAS WITHIN THE KEEP OUT AREA.
- F) DRAWING FILE NAME: PQFN08JREV3.



ON Semiconductor and in are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at <a href="www.onsemi.com/site/pdt/Patent-Marking.pdf">www.onsemi.com/site/pdt/Patent-Marking.pdf</a>. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hold ON Semiconductor and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and exp

#### **PUBLICATION ORDERING INFORMATION**

#### LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor 19521 E. 32nd Pkwy, Aurora, Colorado 80011 USA Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com N. American Technical Support: 800–282–9855 Toll Free USA/Canada
Europe, Middle East and Africa Technical Support: Phone: 421 33 790 2910
Japan Customer Focus Center
Phone: 81–3–5817–1050

ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative